

<b>Notice of References Cited</b>	Application/Control No. 10/780,799		Applicant(s)/Patent Under Reexamination VAWTER ET AL.	
	Examiner Samuel A. Turner		Art Unit 2877	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,661,964	04-1987	Haavisto, John R.	356/461
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP363023211A	02-1988	Japan	Tai et al	---
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	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Recent Developments in Silicon Optoelectronic Devices, Wonk, International Confrence on Microelectronics, IEEE, 5-2002, pp 285-292.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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